## UNITED STATES PATENT AND TRADEMARK OFFICE **CERTIFICATE OF CORRECTION**

PATENT NO.

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Page 1 of 1

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INVENTOR(S) : Sylvie Wuidart and Claude Zahra

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

## Column 3,

Line 45, should read:

-- interval Δt from step 20, an answer request (block 23, SEND --.

## Column 6,

Line 32, should read:

-- said second control signal --.

Lines 43-48, should read:

-- 11. A system for testing a set of identical integrated circuit chips in parallel, comprising:

a plural of physical contact pairs intended to contact pads of the respective chips; and for

transmitting, from a tester a first test control signal to --.

Signed and Sealed this

Eighth Day of November, 2005

JON W. DUDAS Director of the United States Patent and Trademark Office